

## Tutorial 3 E3013 – Etching I

1. Figure 1 shows the isoetch curve for silicon using the HF:HNO<sub>3</sub>:diluent system. If HF:HNO<sub>3</sub>:H<sub>2</sub>O = 50:30:20, determine the etch rate of silicon.

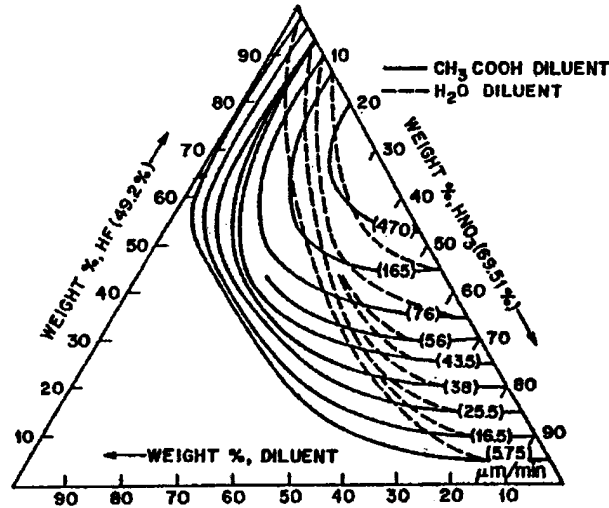


Figure 1 : Isoetch Curves for Silicon

- (a) If the diluent is changed to HC<sub>2</sub>H<sub>3</sub>O<sub>2</sub>, what will be the new etching rate? Explain why the etch rate is usually higher when the diluent is changed to acetic acid.
  - (b) Assuming an etch rate of 56 μm/min and the ratio of HNO<sub>3</sub>: HC<sub>2</sub>H<sub>3</sub>O<sub>2</sub> is maintained at 3:1, what is the %wt of HF used in the etchant.
  - (c) Define etch selectivity. Explain whether physical etching has high etch selectivity. What are the problems associated with physical etching?
  - (d) Suggest ways to increase the etch rate of an RIE system.
2. Figure 2 shows the isoetch curve for the etching of Si wafers.

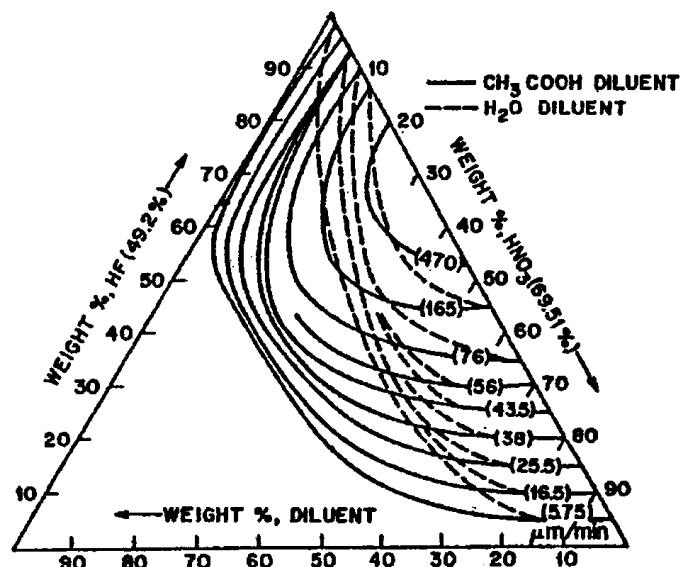
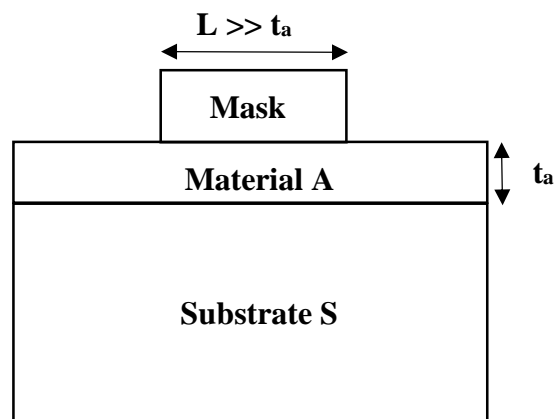


Figure 2 : Isoetch Curves for Silicon

- (a) Draw the 7:3  $\text{HNO}_3$ - $\text{CH}_3\text{COOH}$  load line on the isoetch curve.
- (b) If the etching rate of the silicon is  $56 \mu\text{m}/\text{min}$ , derive the respective percentage of the etchant constituents.

3. Figure 3 shows thin film A (thickness  $t_a$ ) with a patterned photo-resist of feature  $L \gg t_a$  on substrate S. Explain why condition  $L \gg t_a$  is imposed. Complete the table below under the etching condition listed in the table for two etching recipes: (i) no over-etch and (ii) 50% over-etch. The etch selectivity is of A:S is 10:1. State two assumptions about the photoresist.

Profile	Substrate etch depth , $t_s$	Undercut in A, $U_a$
<b>Degree of Anisotropy = 0.70</b>	(i)	(i)
	(ii)	(ii)



**Figure 3**